

Failure Analysis at Infineon Technologies

- Failure Analysis Infineon: HC ca.250 w/w, 180 Europe
- Product FA for all Business Groups Munich& Corporate FA functions + support Munich Fab (5 groups, HC ca 80):
 - \$\ \mathbb{F}\ \text{ roadmap, Readiness for new technologies}
 - ♦ Internal cooordination, External Representation
 - ♥ VDE, EDFAS, SEMATECH, ESREF, ISTFA, IPFA
- Manufacturing assisting PFA groups
 - ⇔ FE 8 sites, 6 in Europe
 - ♦ BE 5 sites, 3 in Europe
 - \$ joint evaluation, investment, roadmap, metrics



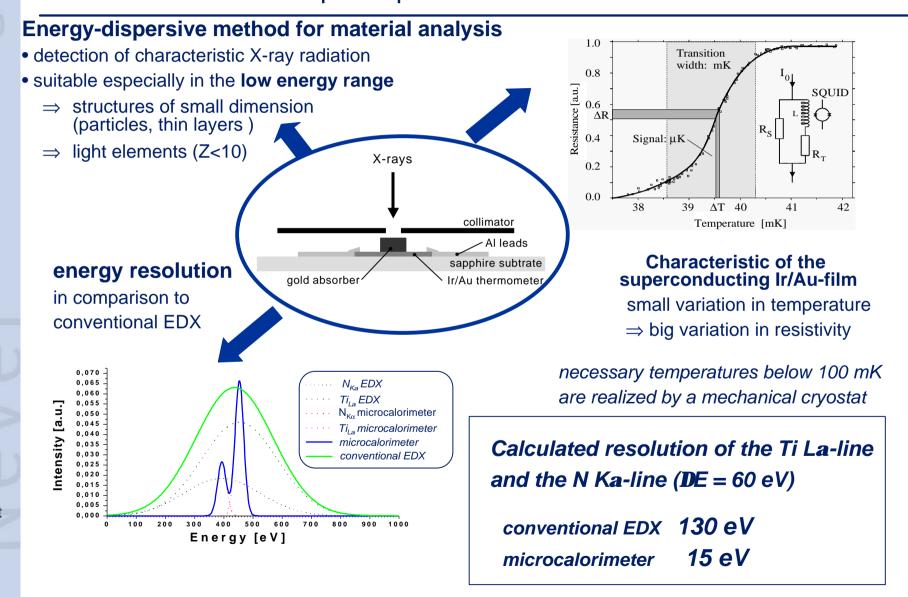
Failure Analysis at Infineon Technologies

■ FA roadmap:

- Backside Analysis (Photoemission, Laser Scanning, LVP,FIB, thermography)
- ♦ Inline Analysis (FIB etc.)
- ♦ Design for Analysis
- ♦ AFM derivatives (funded by government)
- ♥ conductive AFM
- ♦ Microcalorimeter EDX (funded by EU SEA)
- Preparation of new materials
- Integration into development business processes



Microcalorimeter - principle of the detector





Assessment of the detecor / MESA*

Equipment

- Usually serves as detecor in astrophysical applications; is very sensitive to energy of incident radiation
- the detector is installed at a scanning electron microscope
- Supplier: CSP Cryogenic Spectrometers GmbH

Idea

- apply the detector to analytics of semiconductor technology and failure analysis
- problems of future technologies and materials can be solved with this tool,
 while the conventional EDX method fails

Assessment

- assessment of the detector and the mechanical cryostat in a SEA project (MESA*)
 funded by the European Comission
- milestones
 - O initial assessment
 - equipment improvements
 - O final assessment of improved equipment
 - O concept for an inline application

* Microcalorimeter Type EDX System Assessment